



PRODUCT INFORMATION

HTx TEST BENCHES

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- › HTGS – High Temperature Gate Stress
- › HTRB – High Temperature Reverse Bias
- › H3TRB – High Humidity High Temperature Reverse Bias
- › for IGBT, SiC & GaN semiconductors

SPECIFICATIONS

Temperature	up to 225 °C
Test voltage	up to 6.5 kV
Gate control	Voltage: 0 ... +/- 40 V Current: 0 ... 200 mA
Temperature control	$T_{\text{case}} / T_{\text{junc}} / I_{\text{leakage}}$
Configurations	Comprehensive test benches Compact measurement units
Capacity	Up to 120 DUTs per bench
Process software	Automated test sequences Long time logging

Specifications can be adapted to individual requirements.

Contact us

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